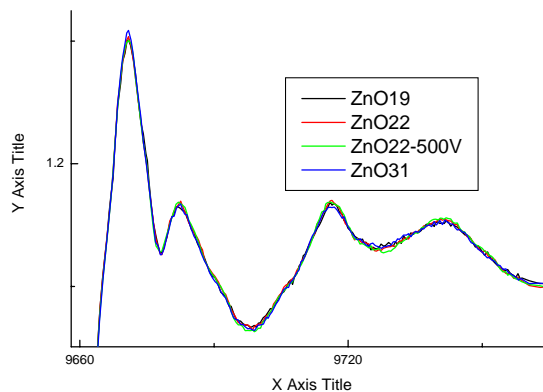
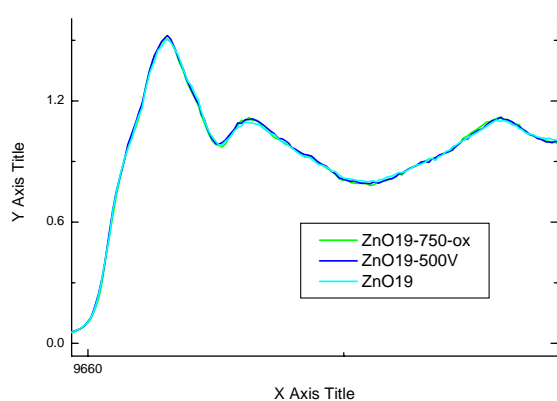
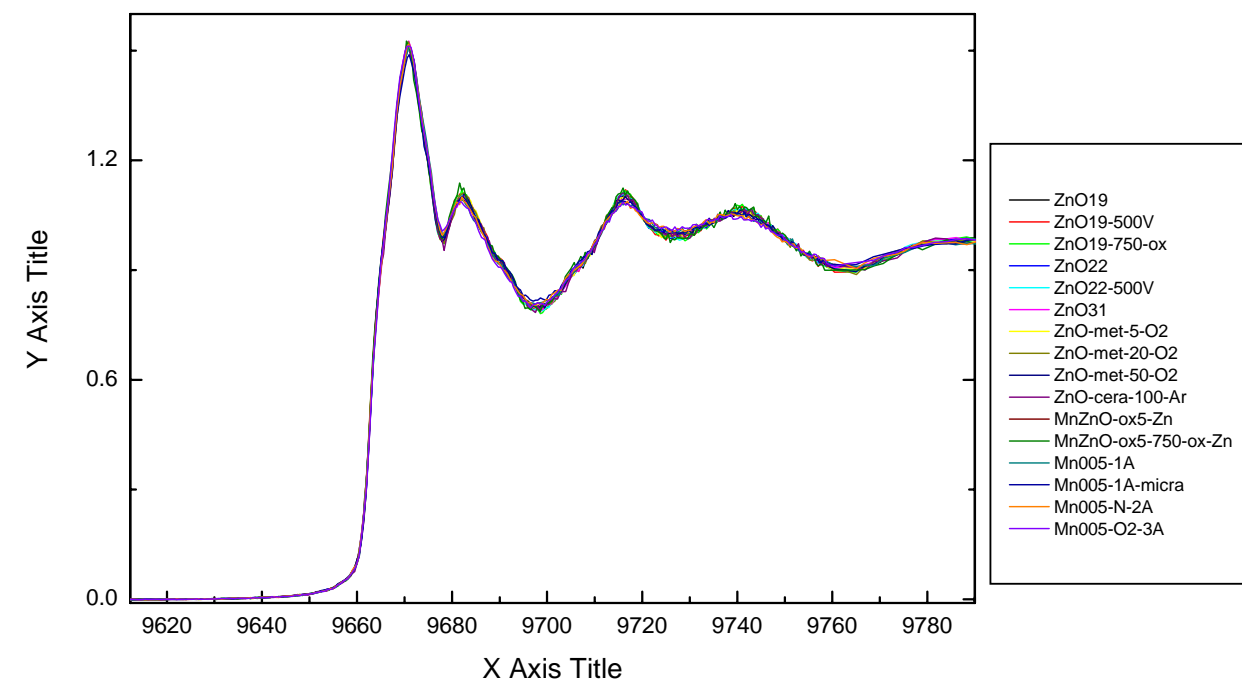


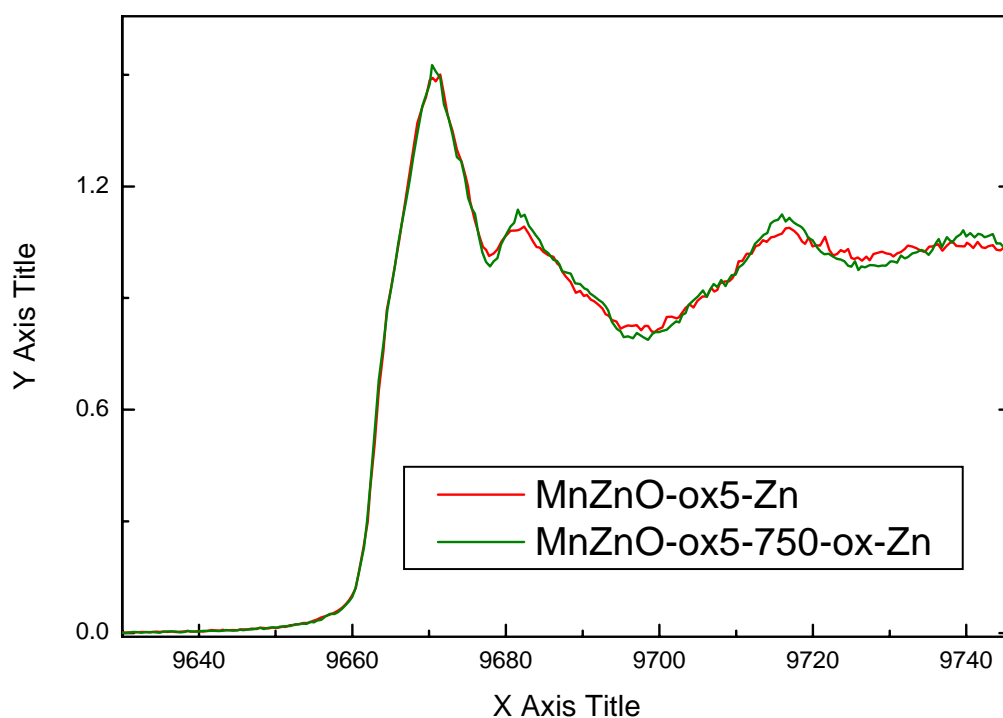
Experiment 25-01-711

a) XANES at Zn K-edge

XANES measurements of 16 different samples (ZnO19, ZnO19-500V, ZnO19-750-ox, ZnO22, ZnO22-50V, ZnO31, ZnO-met-5-O₂, ZnO-met-20-O₂, ZnO-met-50-O₂, ZnO-cera-100-Ar, MnZnO-ox5, MnZnO-ox5-750-O₂, Mn005-1A, Mn005-1A-micra, Mn005-N-2A, Mn005-O2-3A)



Contrary to the Mn K-edge, which results highly sensitive to the sample preparation method, not appreciable differences are found in several samples prepared under very different experimental conditions (different starting sputtering target (metal Zn; ceramic ZnO and different oxygen concentrations). Just very small differences appear in the post-growth annealed samples, where crystal quality improves and intensity of XANES features is slightly increased.



A subtle difference is also found between sample Mn005-1A-micra and the others.

